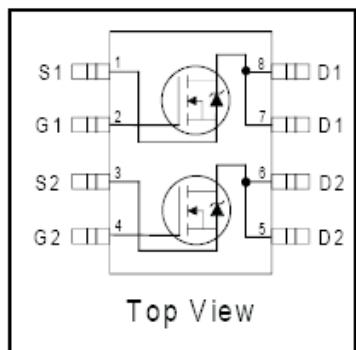
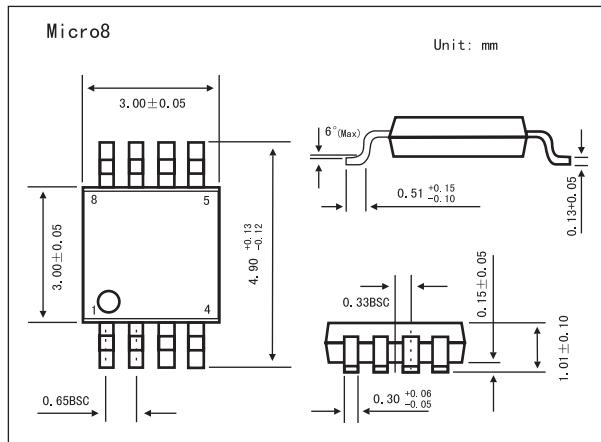


## HEXFET® Power MOSFET

### KRF7501

#### ■ Features

- Generation V Technology
- Ultra Low On-Resistance
- Dual N-Channel MOSFET
- Very Small SOIC Package
- Low Profile (<1.1mm)
- Available in Tape & Reel
- Fast Switching



#### ■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V <sub>DS</sub>	20	A
Continuous Drain Current, V <sub>GS</sub> @ 10V, Ta = 25°C	I <sub>D</sub>	2.4	
Continuous Drain Current, V <sub>GS</sub> @ 10V, Ta = 70°C	I <sub>D</sub>	1.9	A
Pulsed Drain Current*1	I <sub>DM</sub>	19	
Power Dissipation Ta = 25°C *1	P <sub>D</sub>	1.25	W
Power Dissipation Ta = 70°C *1	P <sub>D</sub>	0.8	W
Linear Derating Factor		0.01	W/°C
Gate-to-Source Voltage Single Pulse tp<10 μ s	V <sub>GSM</sub>	16	V
Gate-to-Source Voltage	V <sub>GS</sub>	±12	V
Peak Diode Recovery dv/dt*1	dv/dt	5	V/ns
Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to + 150	°C
Junction-to-Ambient *2	R <sub>θ JA</sub>	100	°C/W

\* I<sub>SD</sub> ≤ 1.7A, di/dt ≤ 66A/μ s, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>, T<sub>J</sub> ≤ 150°C

\*2 Surface mounted on FR-4 board, t ≤ 10sec.

**KRF7501**

■ Electrical Characteristics  $T_a = 25^\circ\text{C}$

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-to-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\ \mu\text{A}$	20			V
Breakdown Voltage Temp. Coefficient	$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	$I_D = 1\text{mA}$ , Reference to $25^\circ\text{C}$		0.041		$\text{V}/^\circ\text{C}$
Static Drain-to-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 4.5\text{V}, I_D = 1.7\text{A}^*1$		0.085	0.135	$\Omega$
		$V_{\text{GS}} = 2.7\text{V}, I_D = 0.85\text{A}^*1$		0.120	0.20	
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\ \mu\text{A}$	0.70			V
Forward Transconductance	$g_{\text{fs}}$	$V_{\text{DS}} = 10\text{V}, I_D = 0.85\text{A}^*1$	2.6			S
Drain-to-Source Leakage Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 16\text{V}, V_{\text{GS}} = 0\text{V}$			1.0	$\mu\text{A}$
		$V_{\text{DS}} = 16\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			25	
Gate-to-Source Forward Leakage	$I_{\text{GSS}}$	$V_{\text{GS}} = 12\text{V}$			-100	$\text{nA}$
Gate-to-Source Reverse Leakage		$V_{\text{GS}} = -12\text{V}$			100	
Total Gate Charge	$Q_g$	$I_D = 1.7\text{A}$		5.3	8.0	$\text{nC}$
Gate-to-Source Charge	$Q_{\text{gs}}$	$V_{\text{DS}} = 16\text{V}$		0.84	1.3	
Gate-to-Drain ("Miller") Charge	$Q_{\text{gd}}$	$V_{\text{GS}} = 4.5\text{V},^*1$		2.2	3.3	
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 10\text{V}$		5.7		$\text{ns}$
Rise Time	$t_r$	$I_D = 1.7\text{A}$		24		
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$	$R_G = 6.0\ \Omega$		15		
Fall Time	$t_f$	$R_D = 5.7\ \Omega$		16		
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}$		260		$\text{pF}$
Output Capacitance	$C_{\text{oss}}$	$V_{\text{DS}} = 15\text{V}$		130		
Reverse Transfer Capacitance	$C_{\text{rss}}$	$f = 1.0\text{MHz}$		61		
Continuous Source Current (Body Diode)	$I_s$	MOSFET symbol showing the integral reverse p-n junction diode.			1.25	$\text{A}$
Pulsed Source Current (Body Diode) *2	$I_{\text{SM}}$				19	
Diode Forward Voltage	$V_{\text{SD}}$	$T_J = 25^\circ\text{C}, I_s = 1.7\text{A}, V_{\text{GS}} = 0\text{V}^*1$			1.2	V
Reverse Recovery Time	$t_{\text{rr}}$	$T_J = 25^\circ\text{C}, I_F = 1.7\text{A}, V_R = 10\text{V}$		39	59	$\text{ns}$
Reverse RecoveryCharge	$Q_{\text{rr}}$	$dI/dt = 100\text{A}/\mu\text{s}^*1$		37	56	$\text{nC}$

\*1 Pulse width  $\leq 300\ \mu\text{s}$ ; duty cycle  $\leq 2\%$ .

\*2 Repetitive rating; pulse width limited bymax

